

Abstract of the Disclosure

The invention relates to a measurement probe, in particular for an apparatus for measurement of the thickness of thin layers, having a housing which has at least one printed circuit board and at least one sensor element which is associated with the printed circuit board, and having a contact cup which is arranged at the lower end of the housing, characterized in that a flexible strip, which has at least one connecting line, is provided on the at least one printed circuit board, and which is passed out of the housing.